

Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/757,334	JAPIKSE ET AL.
Examiner	Art Unit	
Igor Kershteyn	3745	

ISSUE CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
415	001	415	58.4	145	151	914		
INTERNATIONAL CLASSIFICATION								
F	0	4	D	29/44				
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				/				
				/				
<i>John Wurth</i>			11/16/05					
(Assistant Examiner)			(Date)					
<i>K Cooper</i>			11-17-05					
(Legal Instruments Examiner)			(Date)					
Edward K. Look 11/07/05 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)								
						Total Claims Allowed: 38 O.G. Print Claim(s)		
						O.G. Print Fig. 1, 38		

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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7	7	37	67	97	127	157	187
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